

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/654,366	VAN DER ZAAG ET AL.	
		Examiner	Art Unit	Page 1 of 1
		David S Blum	2813	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,576,536 B1	06-2003	Babcock, Carl P.	438/585
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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	T					

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	X	

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	Examiner David S Blum	Art Unit 2813

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-US006461901B1	10-2002	Noguchi	438/158
B	US-US006414164B1	07-2002	Afzali-Ardakani et al	549/59
C	US-US006504175B1	01-2003	Mei et al	257/66
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Stanley Wolf SILICON PROCESSING for the VLSI ERA Vol. 1 Lattice Press 1986 pages 452,468-471,480,501-502
V	John L. Vossen THIN FILM PROCESSES II Academic Press 1991 pages 34-35
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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